



Designation: F 1680 – 07

Standard Test Method for Determining Circuit Resistance of a Membrane Switch¹

This standard is issued under the fixed designation F 1680; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reappraisal. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reappraisal.

1. Scope

1.1 This test method covers the determination of the circuit resistance of a membrane switch.

1.2 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

2. Referenced Documents

2.1 *ASTM Standards:*²

F 2592 Test Method for Measuring the Force-Displacement of a Membrane Switch

3. Terminology

3.1 *Definitions:*

3.1.1 *circuit resistance*—electrical resistance as measured between two test points whose internal contacts, when held closed, complete a circuit.

3.1.2 *membrane switch*—a momentary switching device in which at least one contact is on, or made of, a flexible substrate.

3.1.3 *test points*—two preselected conductive points in a circuit loop, possibly including a switch.

4. Significance and Use

4.1 Resistance is useful to manufacturers and users when designing membrane switch interface circuitry.

5. Apparatus

5.1 *Test Probe*, as defined in Test Method F 2592.

5.2 *Test Surface* to be flat, smooth, unyielding and larger than switch under test.

5.3 *Device*, to hold test probe securely and provide perpendicular movement into and away from switch under test.

5.4 *Resistance Measuring Device*, (for example, ohm meter). The device should not apply a voltage outside the operating range of the switch contacts.

5.5 *Suitable Device*, to apply a controlled and measurable force on the test probe.

6. Procedure

6.1 *Pre-Test Setup:*

6.1.1 Precondition switch until approximation of steady state condition is achieved. (Note this will typically occur between 5 to 25 cycles, and it is recommended that the instrument and test probe be used when practical.)

6.1.2 Secure switch on test surface so that the unit under test can be removed and replaced in the same position after subsequent operations (probe contact position within 0.010 in. of its original position on the switch).

6.1.3 Position test probe over desired area of switch.

6.1.4 Lower probe until tip is just above top surface of switch without touching.

6.1.5 Connect switch terminals to resistance measuring device.

6.2 *In-Process Test:*

6.2.1 Slowly depress switch with probe until the resistance does not change for very small increments of force (for example 28 g).

6.2.2 Slowly retract probe until the resistance shows minimal change.

¹ This test method is under the jurisdiction of ASTM Committee F01 on Electronics and is the direct responsibility of Subcommittee F01.18 on Membrane Switches. Current edition approved July 1, 2007. Published August 2007. Originally published in 1996. Last previous edition approved in 2002 as F 1680–02.

² For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.